



US009318265B2

(12) **United States Patent**
Kamobe et al.

(10) **Patent No.:** **US 9,318,265 B2**
(45) **Date of Patent:** **Apr. 19, 2016**

(54) **MULTILAYER CERAMIC CAPACITOR
PROVIDED WITH EXTERNAL ELECTRODES
PARTIALLY COVERED BY SOLDER
NON-ADHESION FILM**

(71) Applicant: **TAIYO YUDEN CO., LTD.**, Taito-ku,
Tokyo (JP)

(72) Inventors: **Takehiko Kamobe**, Takasaki (JP);
Katsunosuke Haga, Takasaki (JP)

(73) Assignee: **TAIYO YUDEN CO., LTD.**, Tokyo (JP)

(*) Notice: Subject to any disclaimer, the term of this
patent is extended or adjusted under 35
U.S.C. 154(b) by 38 days.

(21) Appl. No.: **14/142,557**

(22) Filed: **Dec. 27, 2013**

(65) **Prior Publication Data**

US 2014/0198427 A1 Jul. 17, 2014

(30) **Foreign Application Priority Data**

Jan. 11, 2013 (JP) 2013-003475

(51) **Int. Cl.**
H01G 4/30 (2006.01)
H01G 4/232 (2006.01)
H01G 4/012 (2006.01)
H01G 4/12 (2006.01)

(52) **U.S. Cl.**
CPC **H01G 4/30** (2013.01); **H01G 4/232**
(2013.01); **H01G 4/2325** (2013.01); **H01G**
4/012 (2013.01); **H01G 4/12** (2013.01)

(58) **Field of Classification Search**
CPC H01G 4/30; H01G 4/2325; H01G 4/232;
H01G 4/012; H01G 4/12
See application file for complete search history.

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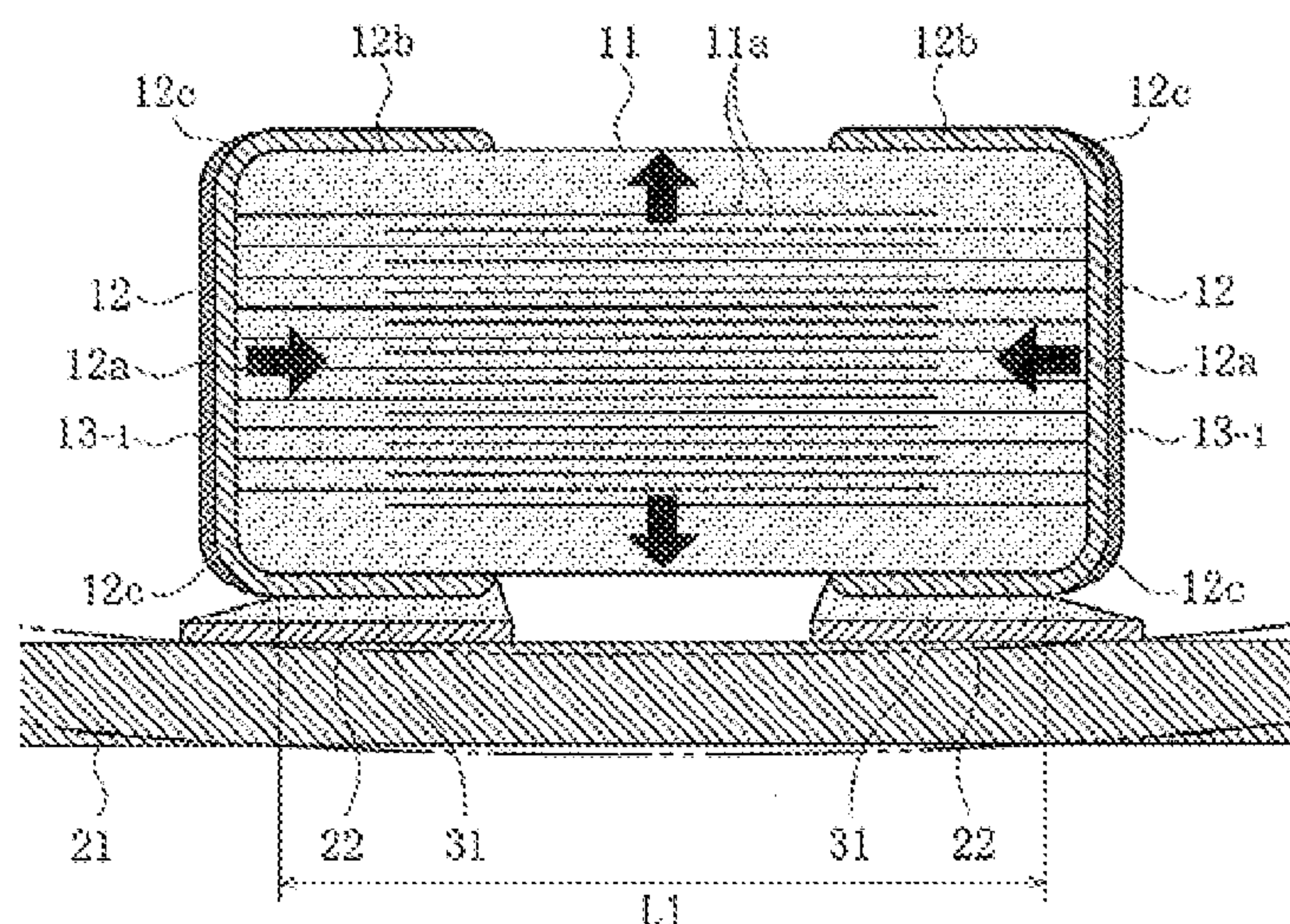
Primary Examiner — David M Sinclair

(74) *Attorney, Agent, or Firm* — Law Office of Katsuhiro
Arai

(57) **ABSTRACT**

A multilayer ceramic capacitor whose external electrodes are
each provided with a solder non-adhesion film made of mate-
rial to which solder does not adhere, in a manner continuously
covering the entire surface of the end face, and optionally the
entire surface of the curved face thereof. The multilayer
ceramic capacitor, with certainty, allows for suppression of
noise accompanying electrostriction.

8 Claims, 5 Drawing Sheets



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Fig. 1
Background Art

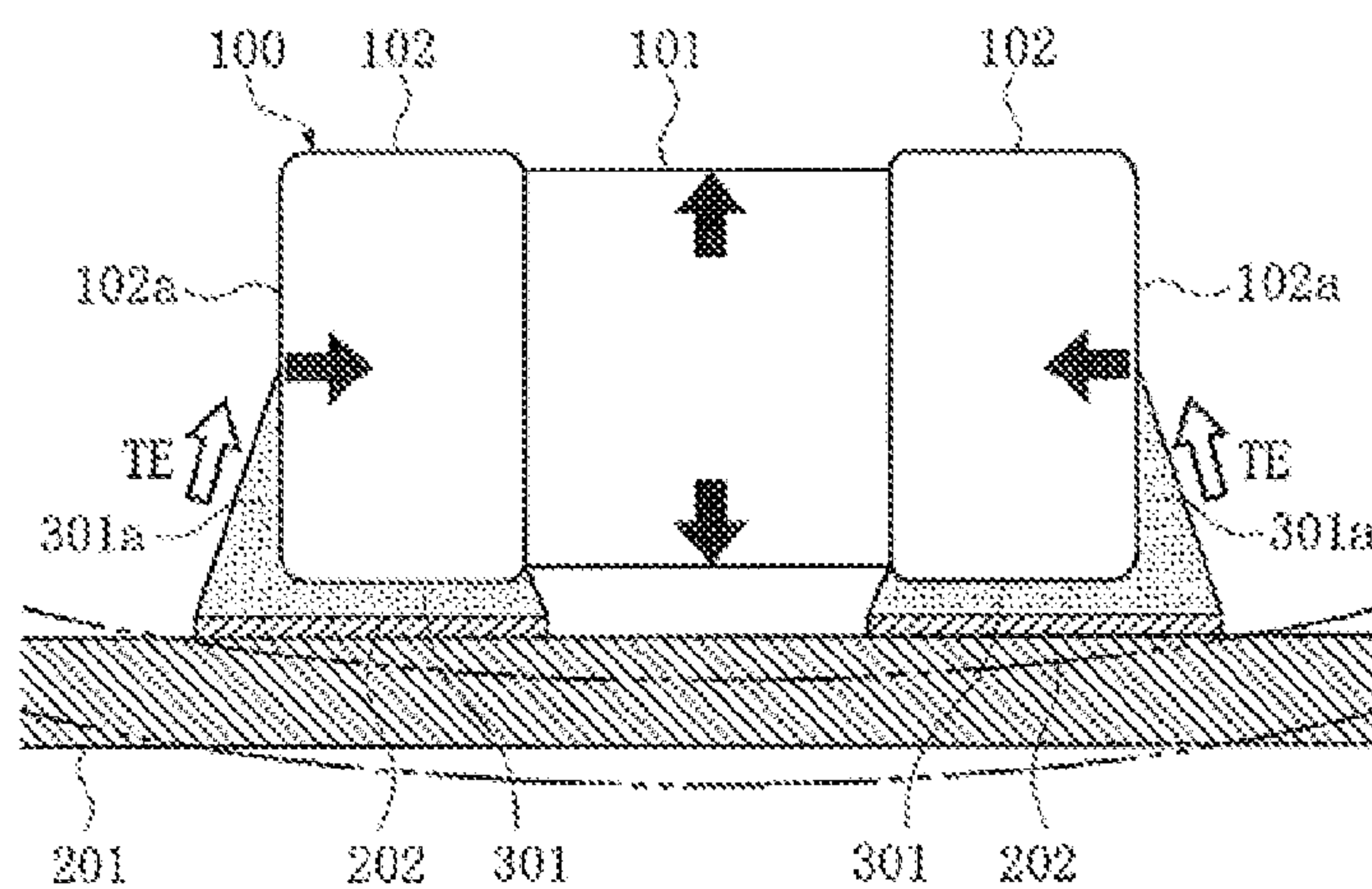


Fig. 2

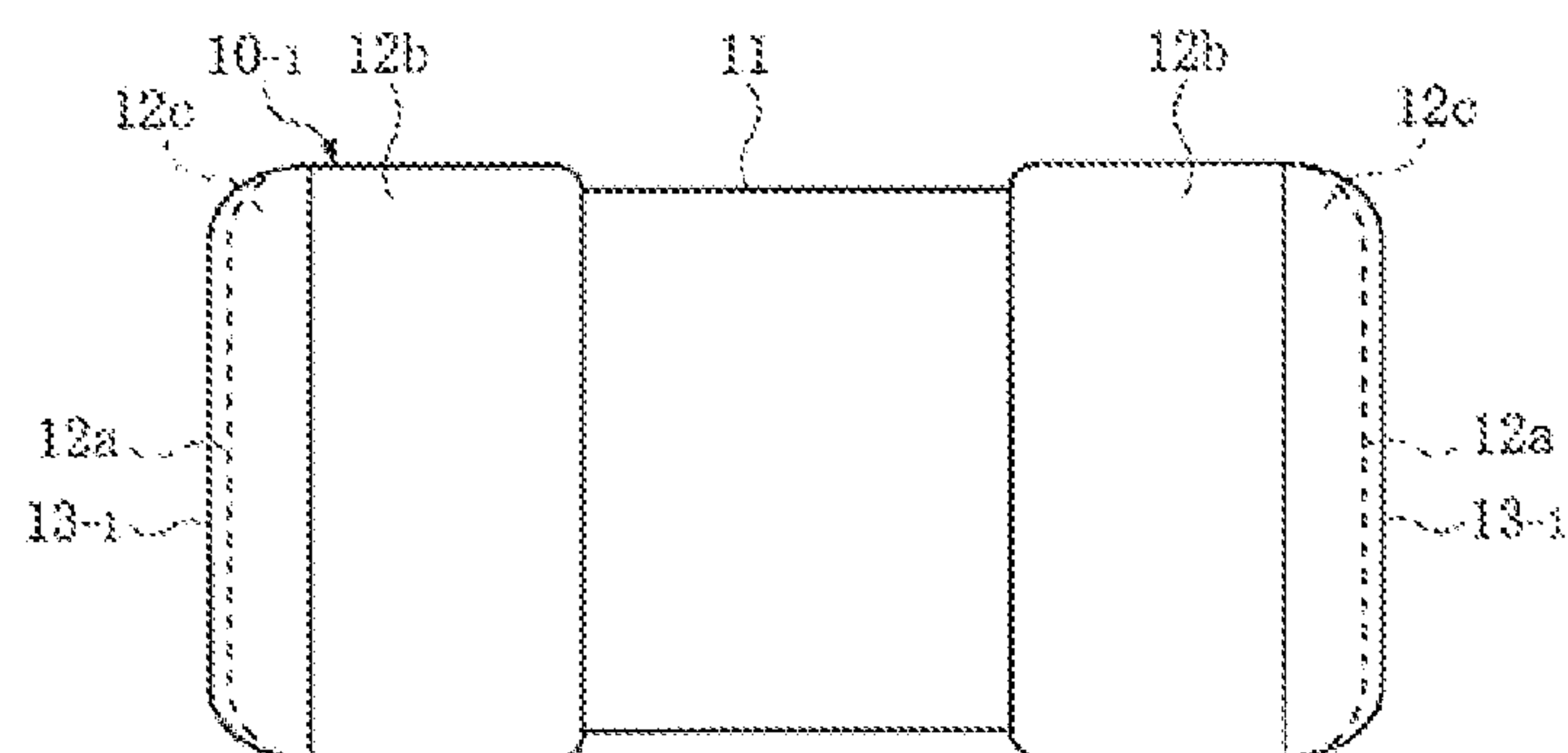


Fig. 3

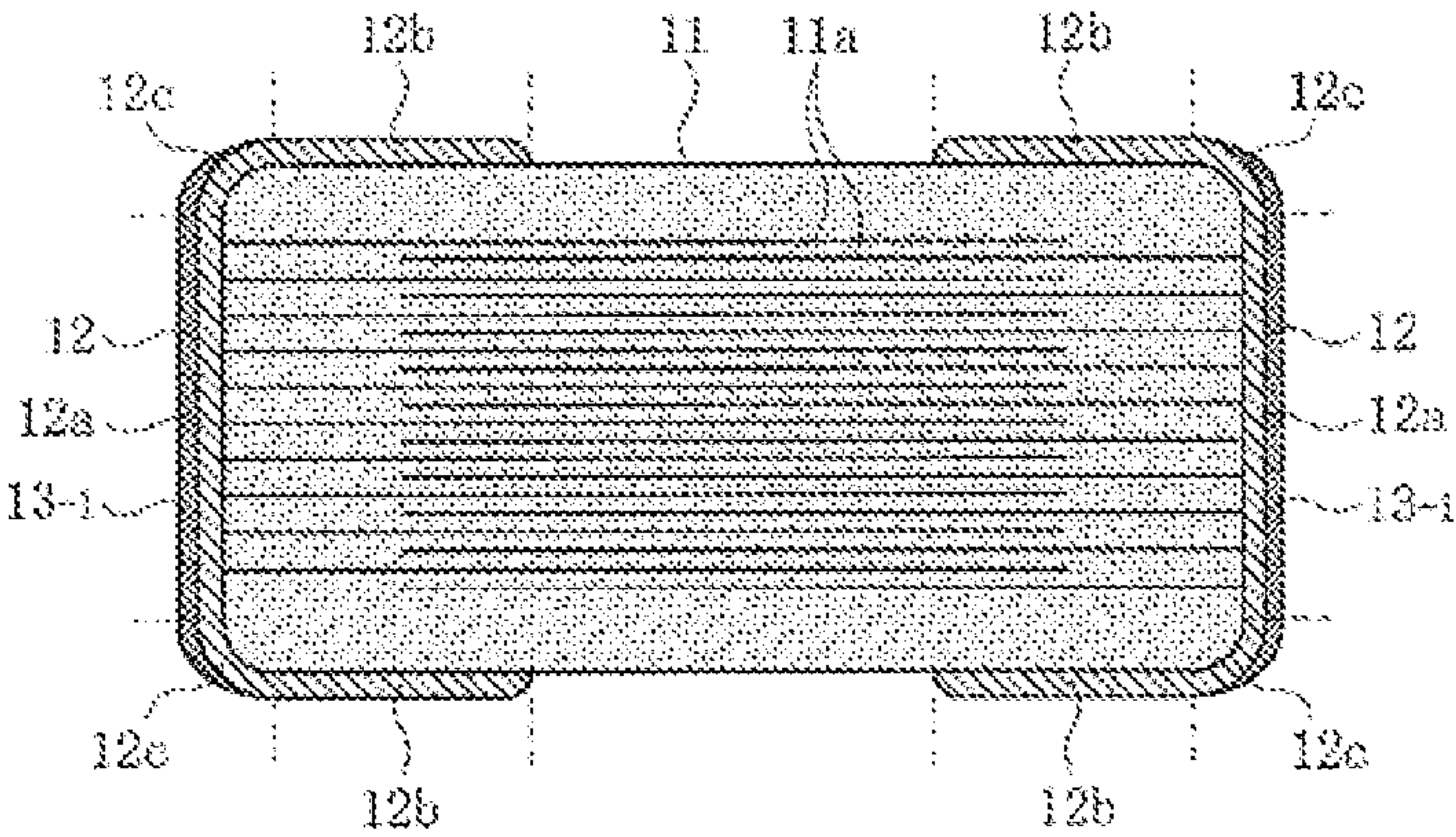


Fig. 4

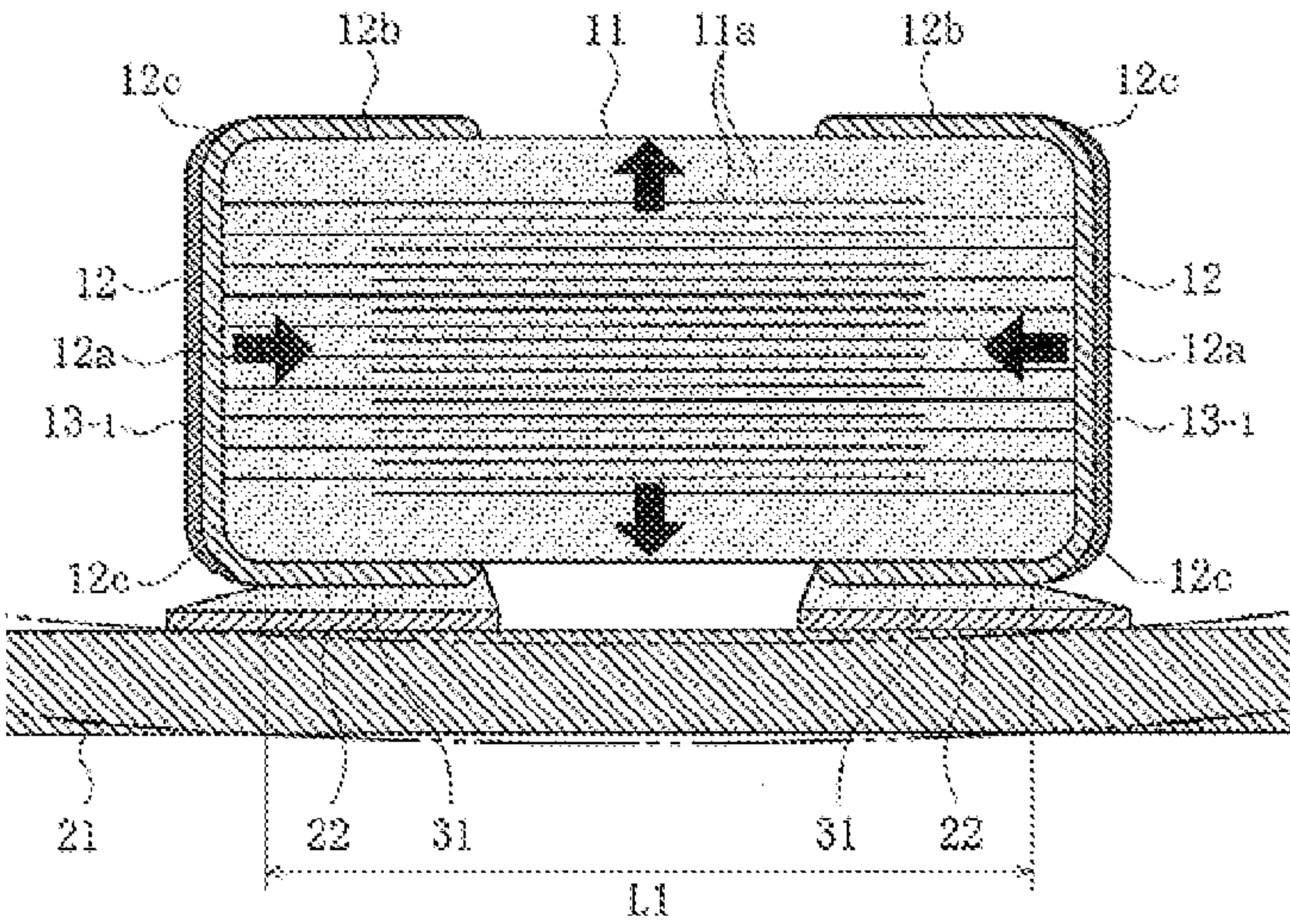


Fig. 5

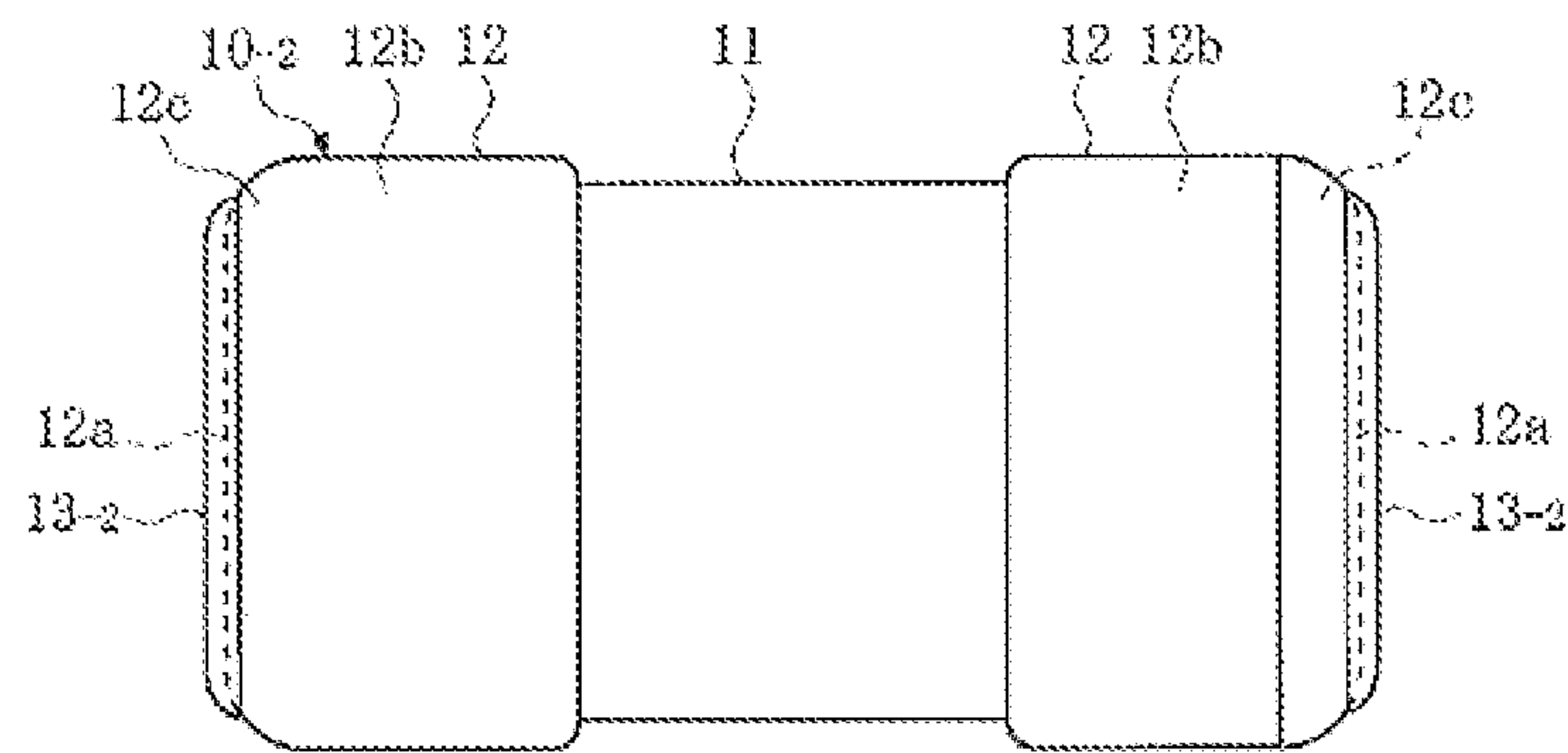


Fig. 6

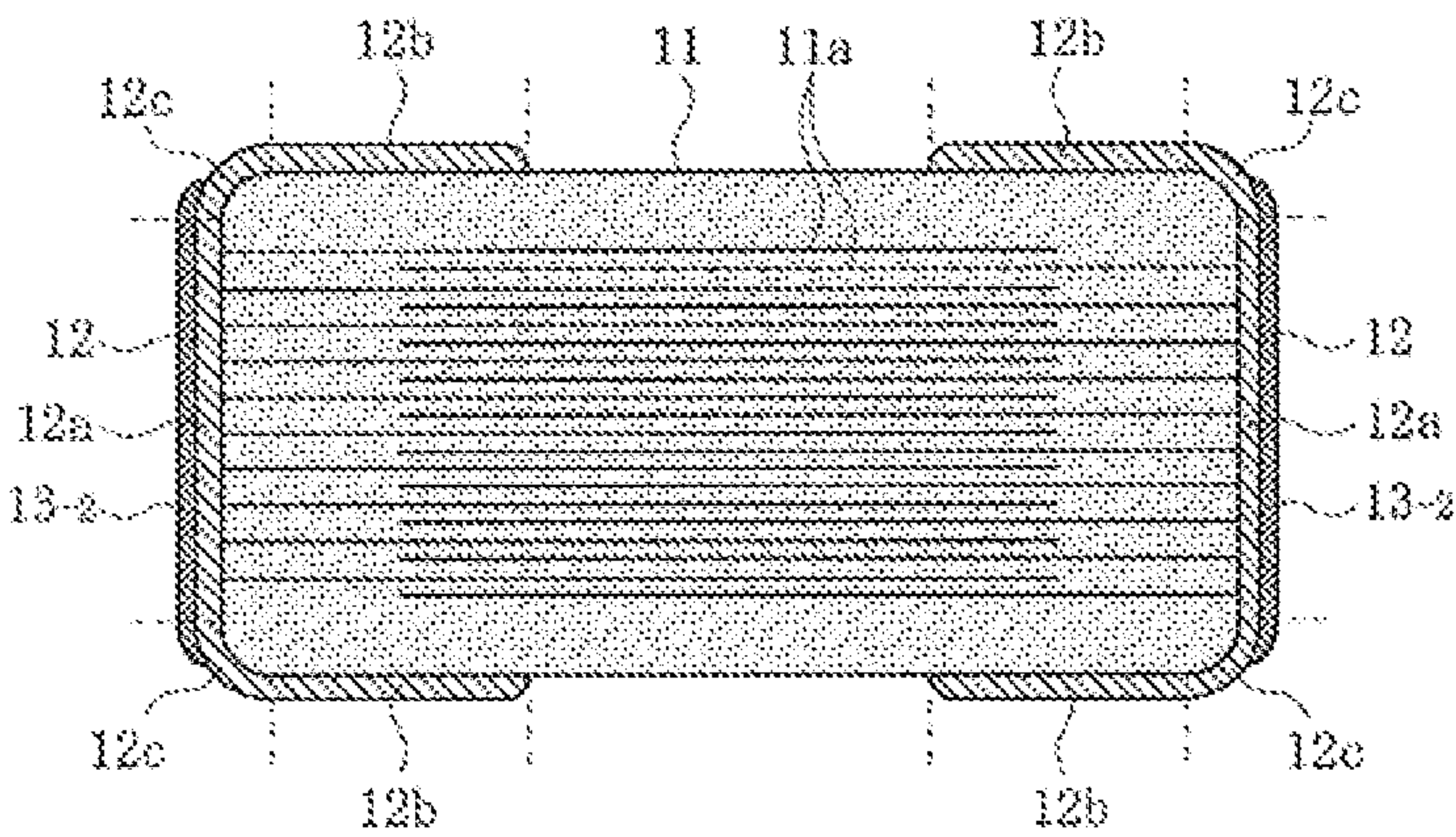


Fig. 7

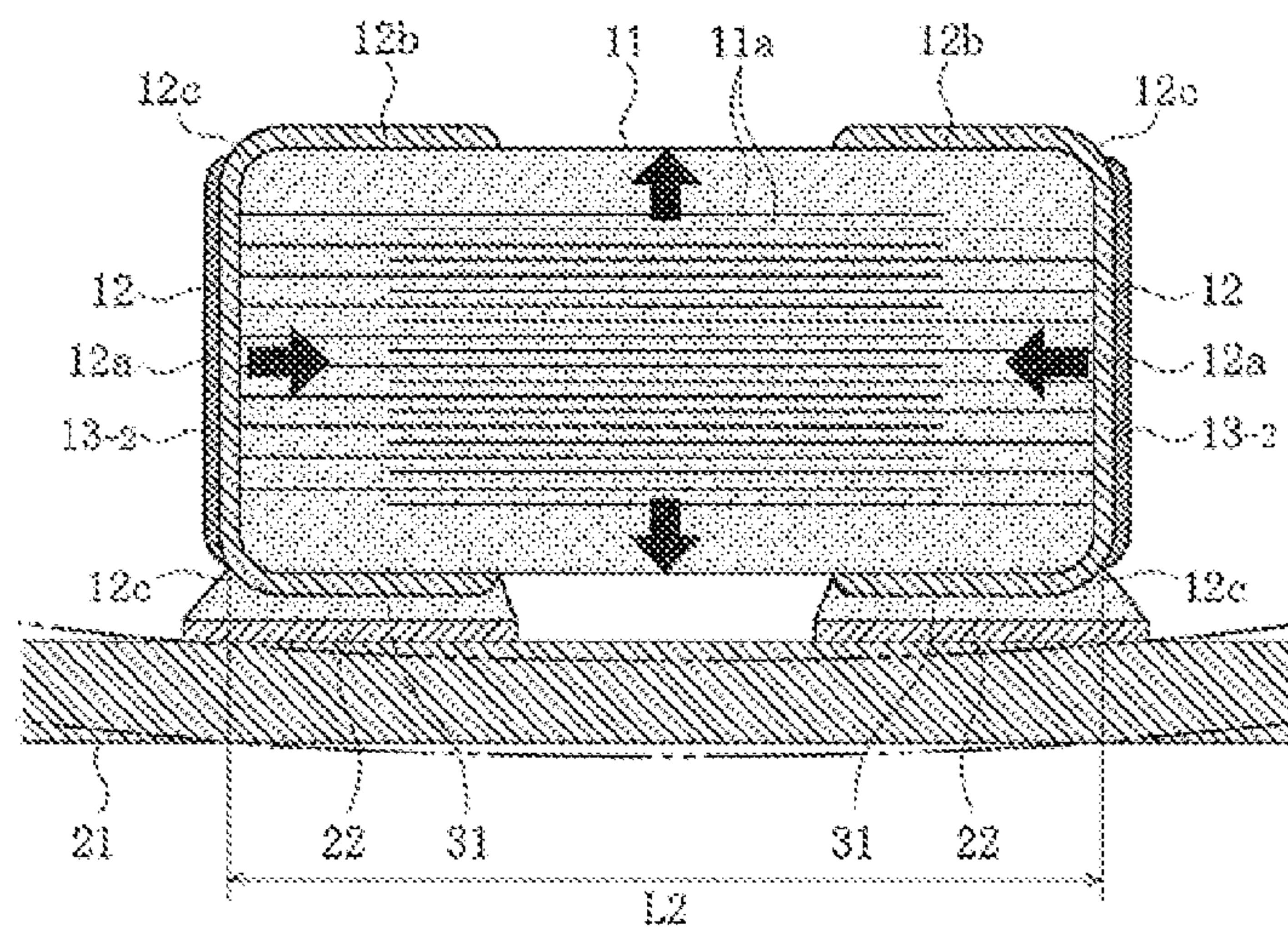


Fig. 8

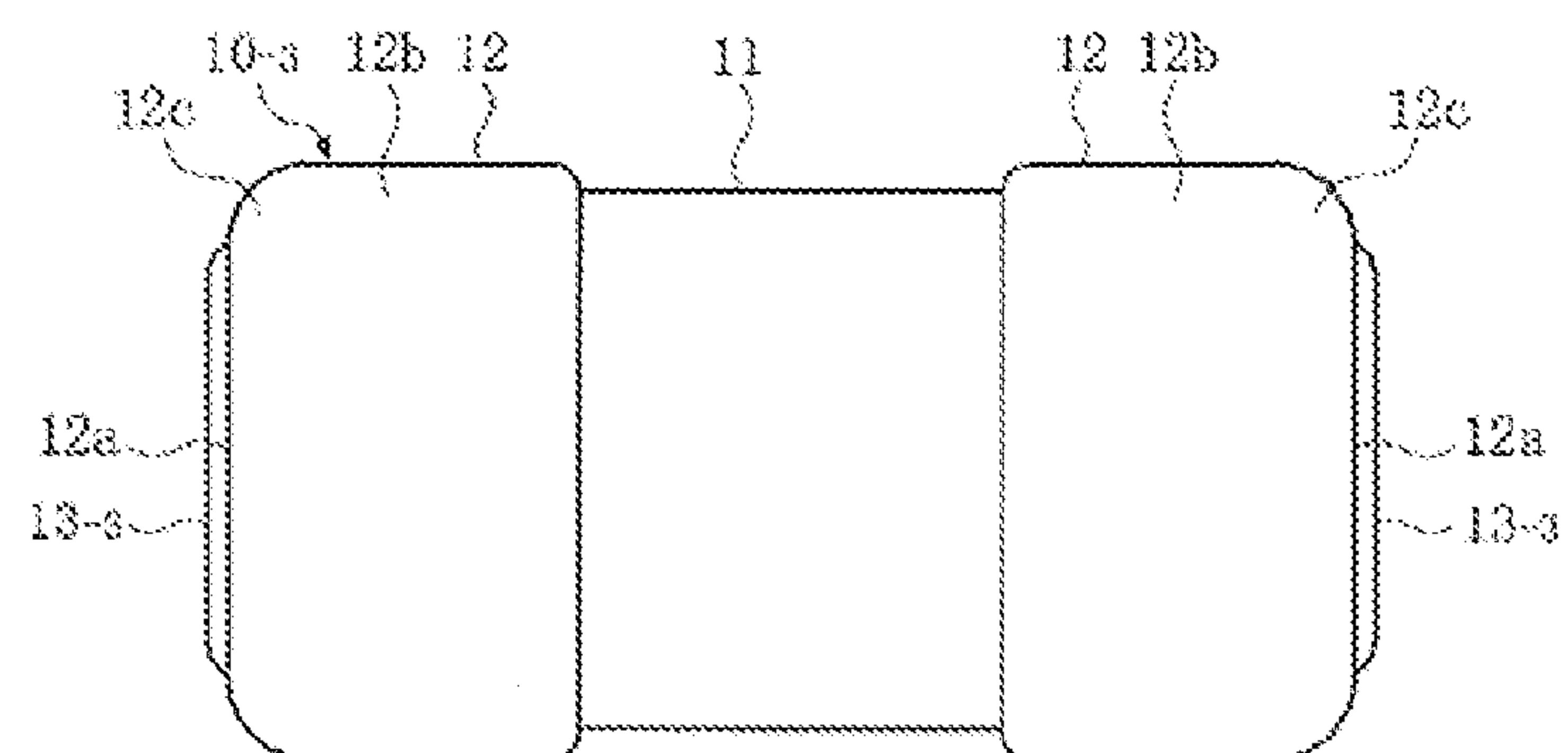


Fig. 9

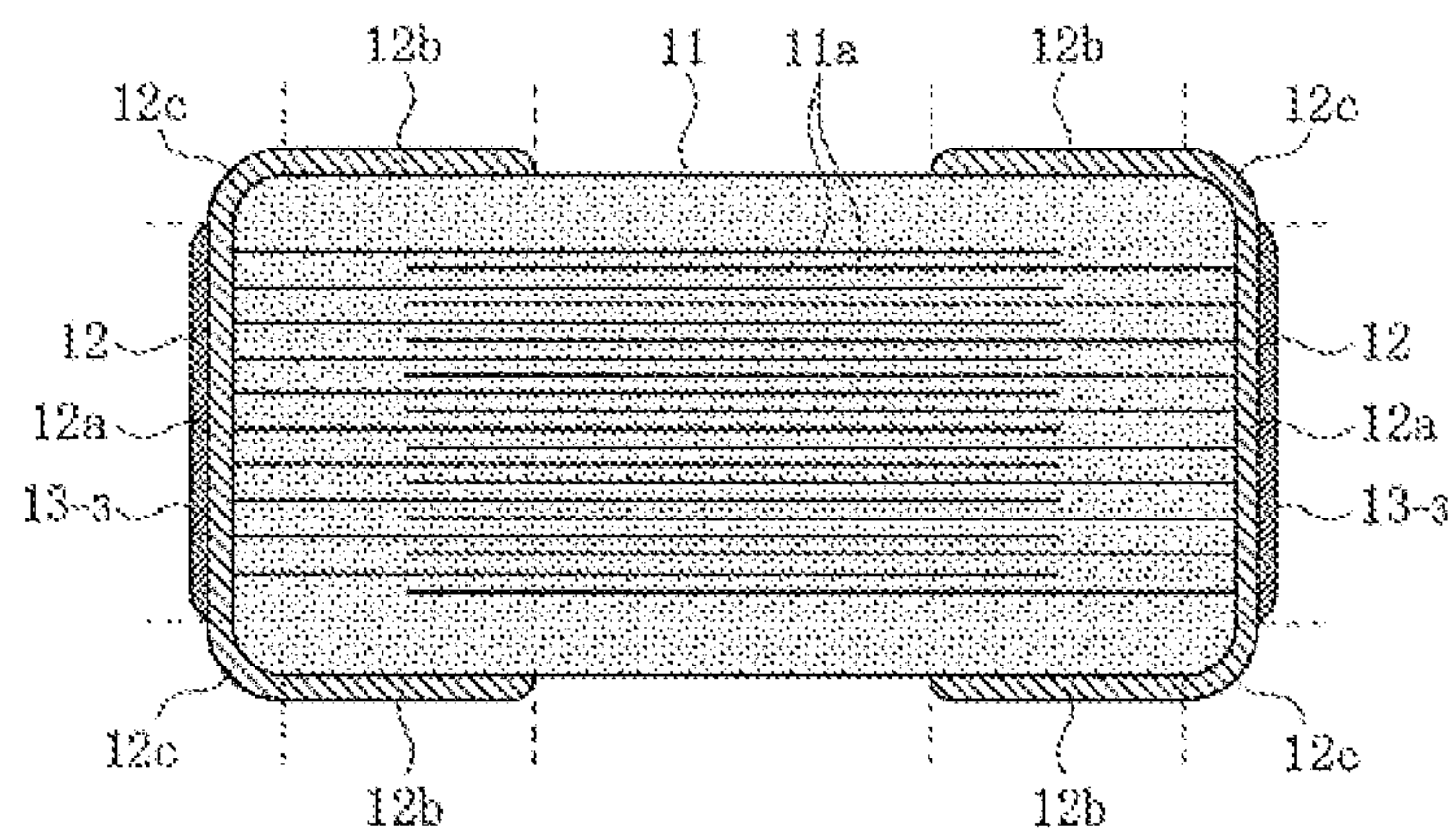
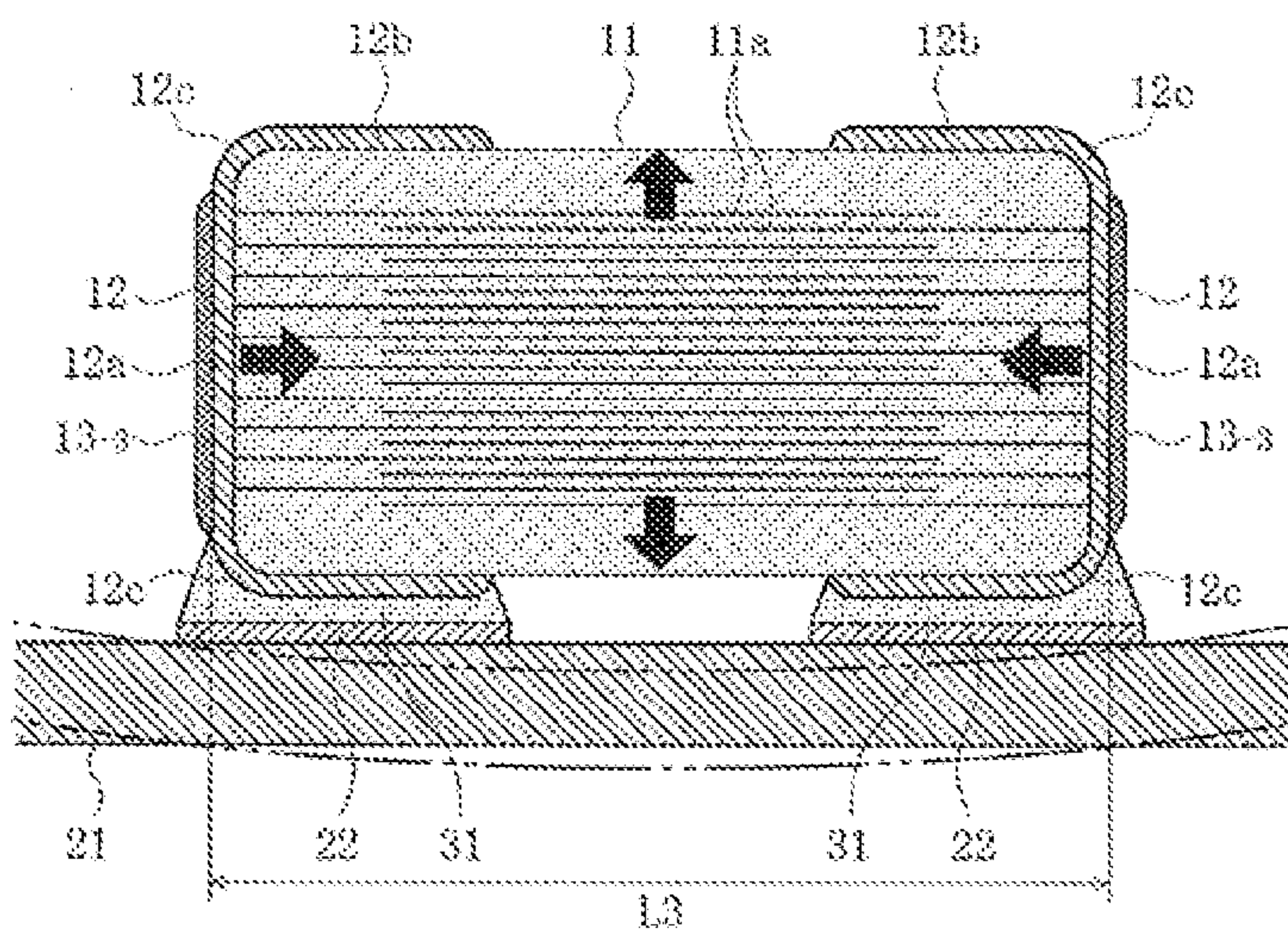


Fig. 10



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**MULTILAYER CERAMIC CAPACITOR
PROVIDED WITH EXTERNAL ELECTRODES
PARTIALLY COVERED BY SOLDER
NON-ADHESION FILM**

FIELD OF THE INVENTION

The present invention relates to a multilayer ceramic capacitor.

DESCRIPTION OF THE RELATED ART

FIG. 1 shows a conventional multilayer capacitor **100** installed on a substrate **201**.

A multilayer ceramic capacitor **100** (hereinafter simply referred to as “capacitor **100**”) comprises a dielectric chip **101** made of dielectric ceramics and having a roughly rectangular shape, as well as external electrodes **102** respectively positioned on the opposing ends thereof, and has a roughly rectangular shape as a whole. The dielectric chip **101** has multiple built-in internal electrode layers (not illustrated) that do not contact each other, where ends of parts of the multiple internal electrode layers (odd-numbered layers from the top) are connected to one external electrode **102**, while ends of the other parts (even-numbered layers from the top) are connected to the other external electrode **102**.

To install this capacitor **100** onto a substrate **201**, the capacitor **100** is installed in such a way that one side face (contacting surface of roughly rectangular shape) of each external electrode **102** comes in contact with a solder paste applied to each pad **202** on the substrate **201**, after which the solder paste is melted by means of reflow soldering or other method of heat treatment and then cured, to join each external electrode **102** to the pad **202** via the solder **301**. Note that the pad **202** on the substrate **201** has a roughly rectangular profile slightly larger than the contacting surface of each external electrode **102**.

Since the molten solder paste behaves in a manner rising on the end face **102a** and side face (side face in the width direction, not shown in this cross sectional view) of each external electrode **102** during the heat treatment, a solder fillet **301a** of a specified height is formed on the end face side of each external electrode **102** of the installed capacitor **100**, as shown in FIG. 1.

Incidentally, if the dielectric chip **101** undergoes electrostriction (i.e., the lateral dimension of the dielectric chip **101** in FIG. 1 decreases while its vertical dimension increases (refer to the black arrows), followed by restoration of the original dimensions, with this process being repeated) due to application of voltage, particularly alternating current voltage, to the installed capacitor **100** as shown in FIG. 1, the substrate **201** may repeatedly warp due to electrostriction (refer to the two-dot chain lines) and resume its original shape to generate vibration, and consequently produce so-called noise due to this vibration.

Particularly when a solder fillet **301a** is formed on the end face side of each external electrode **102** of the installed capacitor **100**, as shown in FIG. 1, the warping (refer to the two-dot chain lines) of the substrate **201** increases and noise generates more easily as a result, due to acting upon the substrate **201** of a tensile force TE (refer to the white arrows) based on the solder fillet **301a**.

Patent Literature 1 cited below describes a multilayer ceramic capacitor having leg terminals on each external electrode **102** in order to suppress the noise accompanying the electrostriction, but if a solder fillet **301a** similar to the one shown in FIG. 1 is formed on the end face side of each leg

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terminal after installation, a tensile force TE (refer to the white arrows in FIG. 1) based on the solder fillet **301a** still acts upon the substrate **201**, although each leg terminal itself does provide an effect of mitigating the transmission of stress to the substrate **201**.

Background Art Literatures

[Patent Literature 1] Japanese Patent Laid-open No. 2004-273935

SUMMARY

An object of the present invention is to provide a multilayer capacitor that allows for, with certainty, suppression of noise accompanying electrostriction.

To achieve the aforementioned object, the present invention provides a multilayer ceramic capacitor comprising a dielectric chip made of dielectric ceramics and having a roughly rectangular shape, as well as external electrodes respectively positioned on the opposing ends thereof, where ends of parts of multiple internal electrode layers built into the dielectric chip in a manner not contacting each other are connected to one external electrode, while ends of the other parts are connected to the other external electrode: wherein each of the external electrodes has an end face of roughly rectangular shape covering an end face of the dielectric chip, a side face of roughly quadrangular cylinder shape covering a part of the four side faces of the dielectric chip, and a curved face of roughly arc cross-section present between the end face and side face; and wherein each of the external electrodes has a solder non-adhesion film made of material to which solder does not adhere: (1) in a manner continuously and exclusively covering the entire surface of the end face and the entire surface of the curved face; (2) in a manner continuously and exclusively covering the entire surface of the end face and a part of the curved face; or (3) in a manner exclusively covering the entire surface of the end face. The term “covering the entire surface” refers to covering the entire surface without any pinholes or any exposed areas, covering a surface to the extent that the covered surface is functionally equivalent to the covered entire surface for the purpose(s) disclosed herein, or covering a substantially or nearly entire surface to the degree effective for the purpose(s) disclosed herein. The term “solder non-adhesion film” refers to a film to which solder does not completely, substantially, or materially adhere, stick, or attach when installing a capacitor on a substrate using the solder so that the solder does not migrate upward along the film during heat treatment.

According to the present invention, a multilayer capacitor can be provided that allows for, with certainty, suppression of noise accompanying electrostriction.

The aforementioned and other objects, and characteristics and effects according to each object, of the present invention are made clear by the explanations given below and drawings attached hereto.

Any discussion of problems and solutions involved in the related art has been included in this disclosure solely for the purposes of providing a context for the present invention, and should not be taken as an admission that any or all of the discussion were known at the time the invention was made.

For purposes of summarizing aspects of the invention and the advantages achieved over the related art, certain objects and advantages of the invention are described in this disclosure. Of course, it is to be understood that not necessarily all such objects or advantages may be achieved in accordance with any particular embodiment of the invention. Thus, for

example, those skilled in the art will recognize that the invention may be embodied or carried out in a manner that achieves or optimizes one advantage or group of advantages as taught herein without necessarily achieving other objects or advantages as may be taught or suggested herein.

Further aspects, features and advantages of this invention will become apparent from the detailed description which follows.

DESCRIPTION OF THE SYMBOLS

10-1, 10-2, 10-3 - - - Multilayer ceramic capacitor, **11** - - - Dielectric chip, **11a** - - - Internal electrode layer, **12** - - - External electrode, **12a** - - - End face, **12b** - - - Side face, **12c** - - - Curved face, **13-1, 13-2, 13-3** - - - Solder non-adhesion film.

BRIEF DESCRIPTION OF THE DRAWINGS

These and other features of this invention will now be described with reference to the drawings of preferred embodiments which are intended to illustrate and not to limit the invention. The drawings are greatly simplified for illustrative purposes and are not necessarily to scale.

FIG. 1 shows a conventional multilayer ceramic capacitor installed on a substrate.

FIG. 2 is a top view of the multilayer ceramic capacitor representing the first embodiment of the present invention.

FIG. 3 is a longitudinal section view of the multilayer ceramic capacitor shown in FIG. 2.

FIG. 4 shows the multilayer ceramic capacitor shown in FIG. 2 as installed on a substrate.

FIG. 5 is a top view of the multilayer ceramic capacitor representing the second embodiment of the present invention.

FIG. 6 is a longitudinal section view of the multilayer ceramic capacitor shown in FIG. 5.

FIG. 7 shows the multilayer ceramic capacitor shown in FIG. 5 as installed on a substrate.

FIG. 8 is a top view of the multilayer ceramic capacitor representing the third embodiment of the present invention.

FIG. 9 is a longitudinal section view of the multilayer ceramic capacitor shown in FIG. 8.

FIG. 10 shows the multilayer ceramic capacitor shown in FIG. 8 as installed on a substrate.

DETAILED DESCRIPTION OF EMBODIMENTS

First Embodiment

FIGS. 2 to 4

FIG. 2 is a top view of a multilayer ceramic capacitor **10-1**, FIG. 3 is a longitudinal section view of the multilayer ceramic capacitor **10-1** shown in FIG. 2, and FIG. 4 shows the multilayer ceramic capacitor **10-1** shown in FIG. 2 as installed on a substrate **21**.

In the explanations provided herein, the lateral dimension of the multilayer ceramic capacitor **10-1** in FIGS. 2 and 3 is referred to as "length," while its vertical dimension in FIG. 2 is referred to as "width" and its vertical dimension in FIG. 3 is referred to as "height," for illustration purposes.

As shown in FIG. 2, the multilayer ceramic capacitor **10-1** (hereinafter simply referred to as "capacitor **10-1**") has an external electrode **12** on each end, in the length direction, of a dielectric chip **11** (i.e., each opposing end of the dielectric chip **11**) made of dielectric ceramics and having a roughly rectangular shape, and forms a roughly rectangular solid

shape whose reference dimensions meet the condition "Length>Width=Height" or "Length>Width>Height" as a whole.

As shown in FIG. 3, the dielectric chip **11** has multiple (a total 20 in FIG. 3) built-in internal electrode layers **11a** that do not contact each other, where ends of parts of the multiple internal electrode layers **11a** (odd-numbered layers from the top) are connected to one (left) external electrode **12**, while ends of the other parts (even-numbered layers from the top) are connected to the other (right) external electrode **12**. Although the total number of internal electrode layers **11a** is 20 in FIG. 3 for illustration purposes, the total number is 100 or more in reality. The dielectric chip **11** is made of barium titanate, strontium titanate, calcium titanate, magnesium titanate, calcium zirconate, calcium zirconate titanate, barium zirconate, titanium oxide or other dielectric ceramics, or preferably dielectric ceramics whose $\epsilon > 1000$ or dielectric ceramics of Class 2 (having a high dielectric constant), where the layer part present in each pair of internal electrode layers **11a** has roughly the same thickness. Each internal electrode layer **11a** is made of nickel, copper, palladium, platinum, silver, gold or alloy thereof or other metal, and has roughly the same thickness and same shape in top view (roughly rectangular).

Each external electrode **12** has a two-layer structure comprising a base layer (not illustrated) contacting the dielectric chip **11** and a surface layer (not illustrated) formed on the surface of the base layer, or a multi-layer structure where at least one intermediate layer (not illustrated) is present between the base layer and surface layer. The base layer is made of nickel, copper, palladium, platinum, silver, gold, or alloy thereof or other metal, the surface layer is made of tin, palladium, gold, zinc, or other metal, and the intermediate layer is made of platinum, palladium, gold, copper, nickel, or other metal.

Each external electrode **12** also has three areas whose boundaries correspond to the broken lines in FIG. 3, which are specifically an end face **12a** of roughly rectangular shape covering an end face of the dielectric chip **11**, a side face **12b** of roughly quadrangular cylinder shape covering a part of the four side faces of the dielectric chip **11**, and a curved face **12c** of roughly arc cross-section present between the end face **12a** and side face **12b**. To supplement the above, the end face **12a** refers to the part covering the surface that specifies the length of the dielectric chip **11**, the side face **12b** refers to the so-called "wrap-around" part, and the curved face **12c** refers to the part whose surface is constituted by a curved surface and which is neither the end face **12a** nor side face **12b**.

Symbol **13-1** represents a solder non-adhesion film made of material to which solder does not adhere, provided in a manner continuously covering the entire surface of the end face **12a**, and entire surface of the curved face **12c**, of each external electrode **12**. FIG. 3 shows the solder non-adhesion film **13-1** whose thickness is roughly constant over the end face **12a** and gradually decreases over the curved face **12c** toward the edge, but given the role of the solder non-adhesion film **13-1** as described later, its thickness over the end face **12a** need not be roughly constant, while its thickness over the curved face **12c** need not gradually decrease toward the edge.

For the material to which solder does not adhere, any insulating material free from metal component can be used favorably, such as: (1) any known solder resist; (2) epoxy resin, phenol resin, polyimide resin, urea resin, melamine resin, unsaturated polyester resin, bis maleimide resin, polyurethane resin, diaryl phthalate resin, silicone resin, cyanate

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resin, or other thermosetting plastic, or (3) silicon dioxide, aluminum oxide, silicon nitride, or other inorganic insulating material.

If any material in (1) or (2) is used, the solder non-adhesion film **13-1** can be produced by, for example, applying an uncured paste and then thermosetting the applied paste, where such method allows the paste to cure at lower temperatures compared to when high-temperature baking is used. If any material in (3) is used, on the other hand, the solder non-adhesion film **13-1** can be produced by, for example, forming a film according to the sputtering method, deposition method, or other thin film forming method.

To install the capacitor **10-1** shown in FIGS. **2** and **3** on a substrate **21**, as shown in FIG. **4**, the capacitor **10-1** is installed in such a way that one side (contacting surface of roughly rectangular shape) of the side face **12b** of each external electrode **12** comes in contact with the solder paste applied to a pad **22** on the substrate **21**, after which the solder paste is melted by means of reflow soldering or other method of heat treatment and then cured, to join each external electrode **12** to the pad **22** via the solder **31**. Note that the pad **22** on the substrate **21** has a roughly rectangular profile slightly larger than the contacting surface of each external electrode **12**.

During the heat treatment, the molten solder paste behaves in a manner rising on the surface of the end face **12a**, and surface of the side face **12b** (side face in the width direction), of each external electrode **12**, but because the solder non-adhesion film **13-1** made of material to which solder does not adhere is provided in a manner continuously covering the entire surface of the end face **12a**, and entire surface of the curved face **12c**, of each external electrode **12**, no solder fillet (refer to symbol **301a** in FIG. **1**) is formed on the side face **12a** side of each external electrode **12** on the installed capacitor **10-1**, as shown in FIG. **4**.

Accordingly, even if the dielectric chip **11** undergoes electrostriction (i.e., the length of the dielectric chip **11** decreases while its height increases (refer to the black arrows), followed by restoration of the original dimensions, with this process being repeated) due to application of voltage, particularly alternating current voltage, to the installed capacitor **10-1** as shown in FIG. **4**, acting upon the substrate **21** of a tensile force TE (refer to the white arrows in FIG. **1**) based on such solder fillet can be prevented to reduce warping (refer to the two-dot chain lines) of the substrate **21**, and this reduced warping in turn mitigates any vibration generating in the substrate **21** and thereby suppresses, with certainty, noise accompanying electrostriction.

In addition, the solder **31** does not adhere to the solder non-adhesion film **13-1** provided in a manner continuously covering the entire surface of the end face **12a**, and entire surface of the curved face **12c**, of each external electrode **12**, and therefore in the installed state shown in FIG. **4**, the outer edge distance L1 of the solder **31** attached to each external electrode **12** can be shortened to less than the length of the capacitor **10-1**, and this shorter outer edge distance L1 reduces warping (refer to the two-dot chain lines) of the substrate **21** further, while this reduced warping further mitigates any vibration generating in the substrate **21**, thereby suppressing noise accompanying electrostriction with greater certainty.

Second Embodiment

FIGS. **5** to **7**

FIG. **5** is a top view of a multilayer ceramic capacitor **10-2**, FIG. **6** is a longitudinal section view of the multilayer ceramic

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capacitor **10-2** shown in FIG. **5**, and FIG. **7** shows the multilayer ceramic capacitor **10-2** shown in FIG. **5** as installed on a substrate **21**.

In the explanations provided herein, the lateral dimension of the multilayer ceramic capacitor **10-2** in FIGS. **5** and **6** is referred to as “length,” while its vertical dimension in FIG. **5** is referred to as “width” and its vertical dimension in FIG. **6** is referred to as “height,” for illustration purposes as in [First Embodiment].

The multilayer ceramic capacitor **10-2** (hereinafter simply referred to as “capacitor **10-2**”) shown in FIGS. **5** and **6** is constitutionally different from the capacitor **10-1** representing the first embodiment in that:

A solder non-adhesion film **13-2** made of material to which solder does not adhere is provided in a manner continuously covering the entire surface of the end face **12a**, and part (roughly a half in FIG. **6**) of the surface of the curved face **12c**, of each external electrode **12**.

FIG. **6** shows the solder non-adhesion film **13-2** whose thickness is roughly constant over the end face **12a** and gradually decreases over the curved face **12c** toward the edge, but given the role of the solder non-adhesion film **13-2** as described later, its thickness over the end face **12a** need not be roughly constant, while its thickness over the curved face **12c** need not gradually decrease toward the edge.

To install the capacitor **10-2** shown in FIGS. **5** and **6** on a substrate **21**, as shown in FIG. **7**, the capacitor **10-2** is installed in such a way that one side (contacting surface of roughly rectangular shape) of the side face **12b** of each external electrode **12** comes in contact with the solder paste applied to a pad **22** on the substrate **21**, after which the solder paste is melted by means of reflow soldering or other method of heat treatment and then cured, to join each external electrode **12** to the pad **22** via the solder **31**. Note that the pad **22** on the substrate **21** has a roughly rectangular profile slightly larger than the contacting surface of each external electrode **12**.

During the heat treatment, the molten solder paste behaves in a manner rising on the surface of the end face **12a**, and surface of the side face **12b** (side face in the width direction), of each external electrode **12**, but because the solder non-adhesion film **13-2** made of material to which solder does not adhere is provided in a manner continuously covering the entire surface of the end face **12a**, and part of the surface of the curved face **12c**, of each external electrode **12**, no solder fillet (refer to symbol **301a** in FIG. **1**) is formed on the side face **12a** side of each external electrode **12** on the installed capacitor **10-2**, as shown in FIG. **7**.

Accordingly, even if the dielectric chip **11** undergoes electrostriction (i.e., the length of the dielectric chip **11** decreases while its height increases (refer to the black arrows), followed by restoration of the original dimensions, with this process being repeated) due to application of voltage, particularly alternating current voltage, to the installed capacitor **10-2** as shown in FIG. **7**, acting upon the substrate **21** of a tensile force TE (refer to the white arrows in FIG. **1**) based on such solder fillet can be prevented to reduce warping (refer to the two-dot chain lines) of the substrate **21**, and this reduced warping in turn mitigates any vibration generating in the substrate **21** and thereby with certainty suppresses noise accompanying electrostriction.

In addition, the solder **31** does not adhere to the solder non-adhesion film **13-2** provided in a manner continuously covering the entire surface of the end face **12a**, and part of the surface of the curved face **12c**, of each external electrode **12**, and therefore in the installed state shown in FIG. **7**, the outer edge distance L2 of the solder **31** attached to each external

electrode **12** can be shortened to less than the length of the capacitor **10-2**, and this shorter outer edge distance **L2** reduces warping (refer to the two-dot chain lines) of the substrate **21** further, while this reduced warping further mitigates any vibration generating in the substrate **21**, thereby suppressing noise accompanying electrostriction with greater certainty.

Furthermore, adhesion of solder **31** to the other parts of the surface of the curved face **12c** of each external electrode **12**, continuously from the side face **12b**, means that the self-alignment effect can be expected from this adhesion of solder **31** to the other parts of the surface of the curved face **12c**.

Third Embodiment

FIGS. 8 to 10

FIG. 8 is a top view of a multilayer ceramic capacitor **10-3**, FIG. 9 is a longitudinal section view of the multilayer ceramic capacitor **10-3** shown in FIG. 8, and FIG. 10 shows the multilayer ceramic capacitor **10-3** shown in FIG. 8 as installed on a substrate **21**.

In the explanations provided herein, the lateral dimension of the multilayer ceramic capacitor **10-3** in FIGS. 8 and 9 is referred to as “length,” while its vertical dimension in FIG. 8 is referred to as “width” and its vertical dimension in FIG. 9 is referred to as “height,” for illustration purposes as in [First Embodiment].

The multilayer ceramic capacitor **10-3** (hereinafter simply referred to as “capacitor **10-3**”) shown in FIGS. 8 and 9 is constitutionally different from the capacitor **10-1** representing the first embodiment in that:

A solder non-adhesion film **13-3** made of material to which solder does not adhere is provided in a manner continuously covering the entire surface of the end face **12a** of each external electrode **12**.

FIG. 9 shows the solder non-adhesion film **13-3** whose thickness is roughly constant over the end face **12a** except for the outer periphery and gradually decreases over the outer periphery toward the edge, but given the role of the solder non-adhesion film **13-3** as described later, its thickness over the end face **12a** except for the outer periphery need not be roughly constant, while its thickness over the outer periphery need not gradually decrease toward the edge.

To install the capacitor **10-3** shown in FIGS. 8 and 9 on a substrate **21**, as shown in FIG. 10, the capacitor **10-3** is installed in such a way that one side (contacting surface of roughly rectangular shape) of the side face **12b** of each external electrode **12** comes in contact with the solder paste applied to a pad **22** on the substrate **21**, after which the solder paste is melted by means of reflow soldering or other method of heat treatment and then cured, to join each external electrode **12** to the pad **22** via the solder **31**. Note that the pad **22** on the substrate **21** has a roughly rectangular profile slightly larger than the contacting surface of each external electrode **12**.

During the heat treatment, the molten solder paste behaves in a manner rising on the surface of the end face **12a**, and surface of the side face **12b** (side face in the width direction), of each external electrode **12**, but because the solder non-adhesion film **13-3** made of material to which solder does not adhere is provided in a manner covering the entire surface of the end face **12a** of each external electrode **12**, no solder fillet (refer to symbol **301a** in FIG. 1) is formed on the side face **12a** side of each external electrode **12** on the installed capacitor **10-3**, as shown in FIG. 10.

Accordingly, even if the dielectric chip **11** undergoes electrostriction (i.e., the length of the dielectric chip **11** decreases while its height increases (refer to the black arrows), followed by restoration of the original dimensions, with this process being repeated) due to application of voltage, particularly alternating current voltage, to the installed capacitor **10-3** as shown in FIG. 10, acting upon the substrate **21** of a tensile force **TE** (refer to the white arrows in FIG. 1) based on such solder fillet can be prevented to reduce warping (refer to the two-dot chain lines) of the substrate **21**, and this reduced warping in turn mitigates any vibration generating in the substrate **21** and thereby with certainty suppresses noise accompanying electrostriction.

In addition, the solder **31** does not adhere to the solder non-adhesion film **13-3** provided in a manner covering the entire surface of the end face **12a** of each external electrode **12**, and therefore in the installed state shown in FIG. 10, the outer edge distance **L3** of the solder **31** attached to each external electrode **12** can be shortened to less than the length of the capacitor **10-3**, and this shorter outer edge distance **L3** reduces warping (refer to the two-dot chain lines) of the substrate **21** further, while this reduced warping further mitigates any vibration generating in the substrate **21**, thereby suppressing noise accompanying electrostriction with greater certainty.

Furthermore, adhesion of solder **31** to the entire surface of the curved face **12c** of each external electrode **12**, continuously from the side face **12b**, means that the self-alignment effect can be expected from this adhesion of solder **31** to the entire surface of the curved face **12c**.

In the present disclosure where conditions and/or structures are not specified, a skilled artisan in the art can readily provide such conditions and/or structures, in view of the present disclosure, as a matter of routine experimentation. Also, in the present disclosure including the examples described above, any ranges applied in some embodiments may include or exclude the lower and/or upper endpoints, and any values of variables indicated may refer to precise values or approximate values and include equivalents, and may refer to average, median, representative, majority, etc. in some embodiments. Further, in this disclosure, an article “a” or “an” may refer to a species or a genus including multiple species, and “the invention” or “the present invention” may refer to at least one of the embodiments or aspects explicitly, necessarily, or inherently disclosed herein. In this disclosure, any defined meanings do not necessarily exclude ordinary and customary meanings in some embodiments.

The present application claims priority to Japanese Patent Application No. 2013-003475, filed Jan. 11, 2013, the disclosure of which is incorporated herein by reference in its entirety.

It will be understood by those of skill in the art that numerous and various modifications can be made without departing from the spirit of the present invention. Therefore, it should be clearly understood that the forms of the present invention are illustrative only and are not intended to limit the scope of the present invention.

We claim:

1. A multilayer ceramic capacitor comprising a dielectric chip made of dielectric ceramics and having a roughly rectangular shape, as well as external electrodes respectively positioned on opposing ends thereof, where ends of parts of multiple internal electrode layers built into the dielectric chip in a manner not contacting each other are connected to one external electrode, while ends of the other parts are connected to the other external electrode, wherein:

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each of the external electrodes has an end face of roughly rectangular shape covering an end face of the dielectric chip, a side face of roughly quadrangular cylinder shape covering a part of four side faces of the dielectric chip, and a curved face of roughly arc cross-section present between the end face and side face; and

each of the external electrodes has a solder non-adhesion film made of material to which solder does not adhere, said solder non-adhesion film continuously and exclusively covering an entire surface of the end face and a part or an entire surface of the curved face without covering the side face wherein a distance between an edge of the solder non-adhesion film on one end of the capacitor and an edge of the solder non-adhesion film on the other end of the capacitor, which corresponds to an outer edge distance of solder to be attached to each external electrode, is shorter than a length of the dielectric chip.

2. A multilayer ceramic capacitor according to claim 1, wherein the material to which solder does not adhere is an insulating material free from metal component.

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3. A multilayer ceramic capacitor according to claim 2, wherein the dielectric ceramics is dielectric ceramics whose $\epsilon > 1000$ or dielectric ceramics of Class 2.

4. A multilayer ceramic capacitor according to claim 3, wherein a total number of the multiple internal electrode layers is 100 or more.

5. A multilayer ceramic capacitor according to claim 2, wherein a total number of the multiple internal electrode layers is 100 or more.

6. A multilayer ceramic capacitor according to claim 1, wherein the dielectric ceramics is dielectric ceramics whose $\epsilon > 1000$ or dielectric ceramics of Class 2.

7. A multilayer ceramic capacitor according to claim 6, wherein a total number of the multiple internal electrode layers is 100 or more.

8. A multilayer ceramic capacitor according to claim 1, wherein a total number of the multiple internal electrode layers is 100 or more.

* * * * *

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 9,318,265 B2
APPLICATION NO. : 14/142557
DATED : April 19, 2016
INVENTOR(S) : Takehiko Kamobe and Katsunosuke Haga

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In the specification,

At column 4, line 17, in “whose $E > 1000$ or dielectric”, please delete “ \in ” and insert therefor ϵ .

In the claims,

At column 10, line 3, in Claim 3, “whose $E > 1000$ or dielectric”, please delete “ \in ” and insert therefor ϵ .

At column 10, line 12, in Claim 6, “whose $E > 1000$ or dielectric”, please delete “ \in ” and insert therefor ϵ .

Signed and Sealed this
Twenty-first Day of June, 2016



Michelle K. Lee
Director of the United States Patent and Trademark Office